

SN54S436, SN74S436 LINE DRIVER/MEMORY DRIVER CIRCUITS

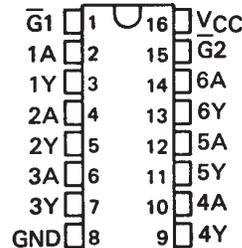
SDLS211 – JANUARY 1981 – REVISED MARCH 1988

MOS MEMORY INTERFACE

- Can Drive High-Impedance Loads
- Interchangeable with National DS16149 DS16179 Drivers
- High-Speed Switching
- Minimum Input Current Required
- Damping Output Resistor Reduces Transients

SN54S436 . . . J OR W PACKAGE
SN74S436 . . . D OR N PACKAGE

(TOP VIEW)



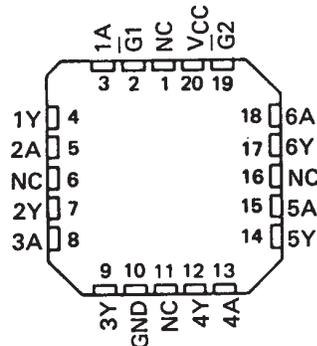
description

The SN54S436 and SN74S436 are monolithic integrated TTL-to-MOS drivers and interface circuits. The p-n-p input transistors use minimum current allowing increased fan-out to these drivers. Schottky-clamped transistor logic permits high-speed operation, minimum propagation time.

The small series damping resistor has been included in the design of the 'S436 to eliminate undesired output transient overshoot. Either enable, \bar{G} , when high, sets the outputs to the high level for MOS RAM refresh applications.

SN54S436 . . . FK PACKAGE

(TOP VIEW)



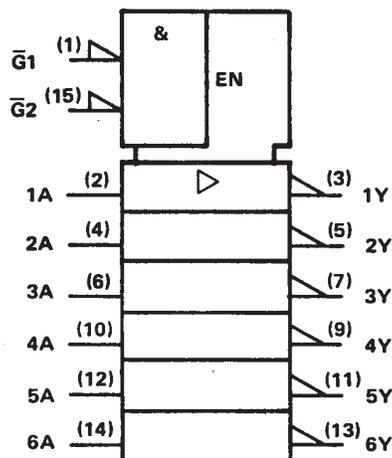
NC - No internal connection

FUNCTION TABLE

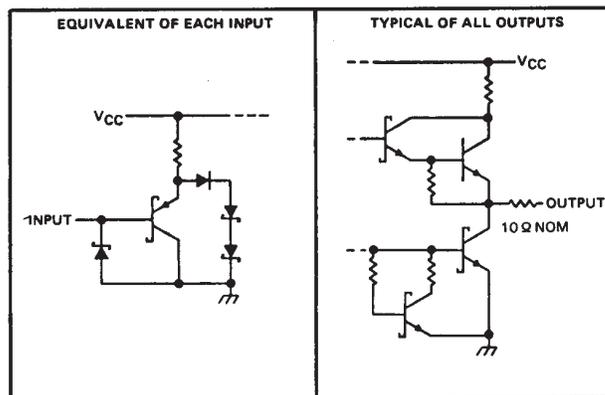
ENABLE INPUTS		INPUT	OUTPUT
$\bar{G}1$	$\bar{G}2$		
L	L	L	H
L	L	H	L
X	H	X	H
H	X	X	H

H = high level, L = low level, X = irrelevant

logic symbol†



schematics of inputs and outputs



†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage range	-1.5 to 7 V
Continuous total dissipation at (or below) 25°C free-air temperature (see Note 2)	
J package	1375 mW
N package	1150 mW
W package	1000 mW
Operating free-air temperature range: SN54S436	-55°C to 125°C
SN74S436	0°C to 70°C
Storage temperature range	-65°C to 150°C

- NOTES: 1. All voltage values are with respect to network ground terminal.
 2. For operation above 25°C free-air temperature, derate as follows: J package, 11.0 mW/°C, N package, 9.2 mW/°C, W package, 8.0 mW/°C.

recommended operating conditions

		SN54S436			SN74S436			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
T_A	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	SN54S436			SN74S436			UNIT
		MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$	-0.75		-1.2	-0.75		-1.2	V
V_{OH}	$V_{CC} = \text{MIN}, I_{OH} = -10 \mu\text{A}$	3.4	4.3		3.5	4.3		V
	$V_{CC} = \text{MIN}, I_{OH} = -1 \text{ mA}$	'S436 2.4	3.5		'S436 2.6	3.5		
V_{OL}	$V_{CC} = \text{MIN}, I_{OL} = 10 \mu\text{A}$		0.25	0.4		0.25	0.35	V
	$V_{CC} = \text{MIN}, I_{OL} = 20 \text{ mA}$	'S436 0.6		1.1	'S436 0.6		1	
		'S437 0.4		0.5	'S437 0.4		0.5	
I_{OL}	$V_{CC} = \text{MIN}, V_O = 4.5 \text{ V}, V_I = 2 \text{ V}$ See Note 3		150	200		150	200	mA
$I_{OS}‡$	$V_{CC} = \text{MAX}, V_O = 0 \text{ V}$	-100	-250	-400	-100	-250	-400	mA
I_I	$V_{CC} = \text{MAX}, V_{IH} = 5.5 \text{ V}$			1			1	mA
I_{IH}	$V_{CC} = \text{MAX}, V_{IH} = 2.7 \text{ V}$		0.1	50		0.1	50	μA
I_{IL}	$V_{CC} = \text{MAX}, V_{IL} = 0.5 \text{ V}$		-100	-250		-100	-250	μA
I_{CC}	$V_{CC} = \text{MAX}, G$ inputs at 0 V, All other inputs at 4.5 V		33	60		33	60	mA
	$V_{CC} = \text{MAX},$ All inputs at 0 V		14	20		14	20	

† All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$.

‡ Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.



switching characteristics, $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{AHL}	Delay time from A high to Y starting low	See Figure 1	$C_L = 50\text{ pF}$	4.5	7		ns
			$C_L = 500\text{ pF}$	12	16		
t_{ALH}	Delay time from A low to Y starting high	See Figure 1	$C_L = 50\text{ pF}$	5	8		ns
			$C_L = 500\text{ pF}$	11	16		
t_{GHYH}	Delay time from G high to Y starting high	$R_L = 2\text{ k}\Omega$ to Gnd, See Figure 2	$C_L = 50\text{ pF}$,	10	18		ns
t_{GLYL}	Delay time from G low to Y starting low	$R_L = 2\text{ k}\Omega$ to V_{CC} , See Figure 3	$C_L = 50\text{ pF}$,	11	18		ns
t_{THL}	Transition time, high-to-low-level output	See Figure 1	$C_L = 50\text{ pF}$	5	8		ns
			$C_L = 500\text{ pF}$	15	30		
t_{TLH}	Transition time, low-to-high-level output	See Figure 1	$C_L = 50\text{ pF}$	6	9		ns
			$C_L = 500\text{ pF}$	15	30		

PARAMETER MEASUREMENT INFORMATION

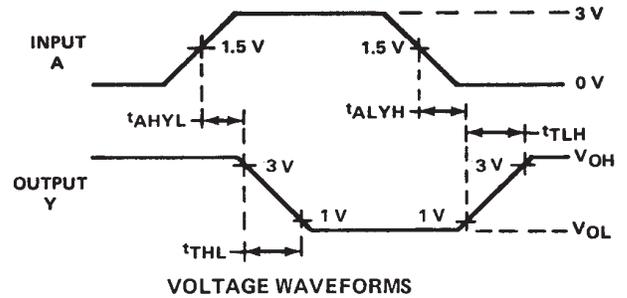
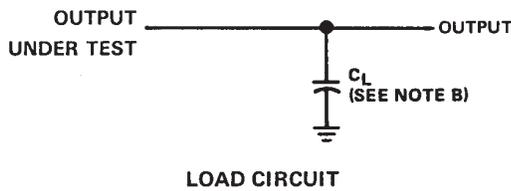


FIGURE 1

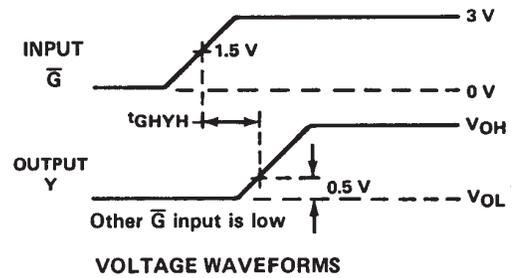
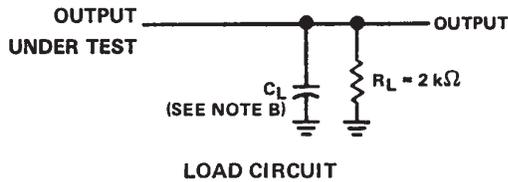


FIGURE 2

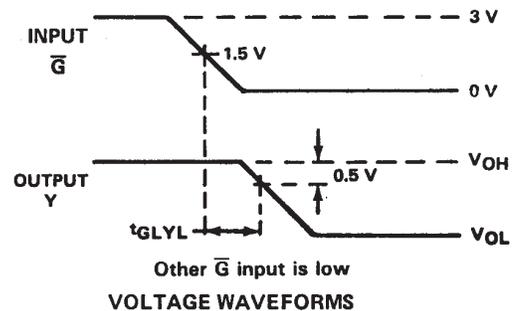
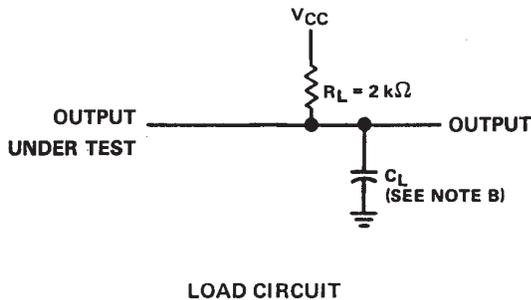


FIGURE 3

NOTES: A. Input pulses are supplied by a generator having the following characteristics: $PRR < 1\text{ MHz}$, $Z_{out} \approx 50\ \Omega$, $t_r < 5\text{ ns}$.
B. C_L includes probe and jig capacitance.

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